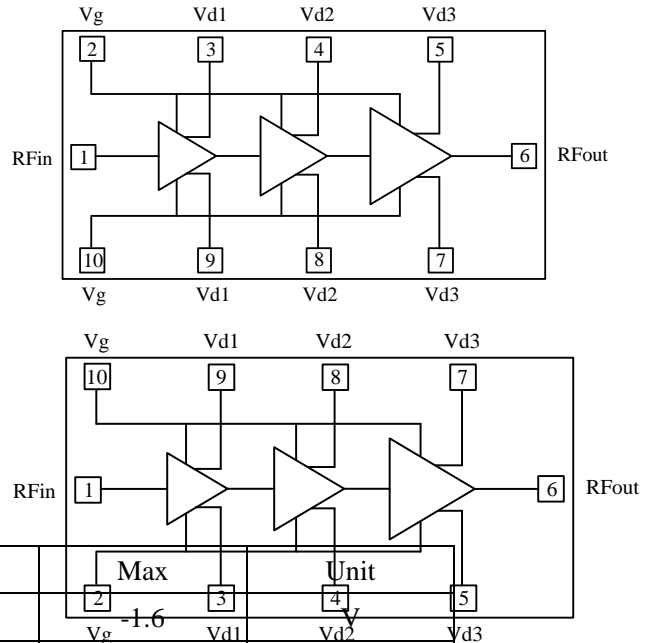


Feature

- Frequency : 15.5GHz~17.5GHz
- Power Gain: 20dB
- Psat: 47dBm
- PAE: 30%
- +28V@3.0A(Quiescent)
- Dimension : 3.60mm×5.90mm×0.10mm

Function Diagram



DC Electrical Specification (TA = +25°C)

Parameter	Min	Typical	Max	Unit
Vd	-2.2	-2.0	-1.6	V
Vg	24	28	32	V
Id	3.5	4.0	4.5	A
Idd		6.0	6.5	A
Ig		0.1	1	mA
Igg		2	10	mA

Microwave Electrical Specification (TA = +25°C, Vd = +28V, Vg = -2.0V)

Parameter	Min	Typical	Max	Unit
f	15.5~17.5			GHz
Psat	47	47.8		dBm
Gp	19	20		dB
ΔGp			±0.5	dB
PAE	30	35		%
Gain	28	30	33	dB
ΔGain			±2.5	dB
VSWR(in)		2.0	2.5	-
Second Harmonic			-30	dBc

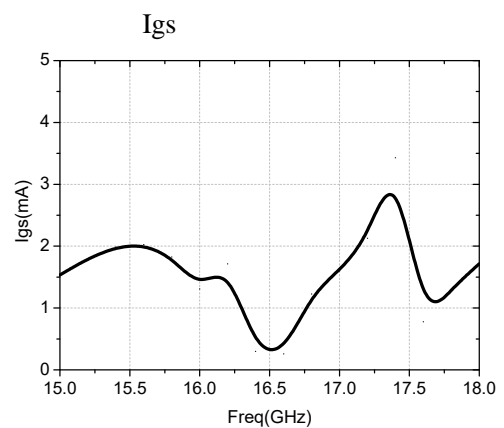
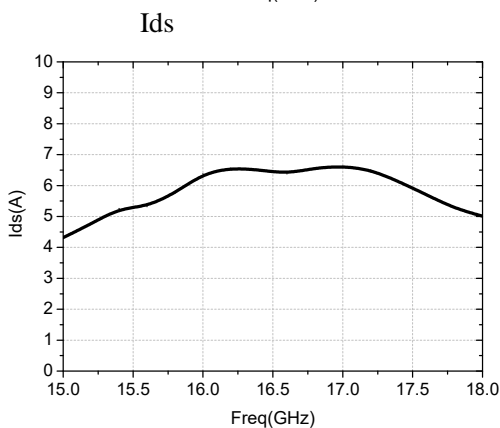
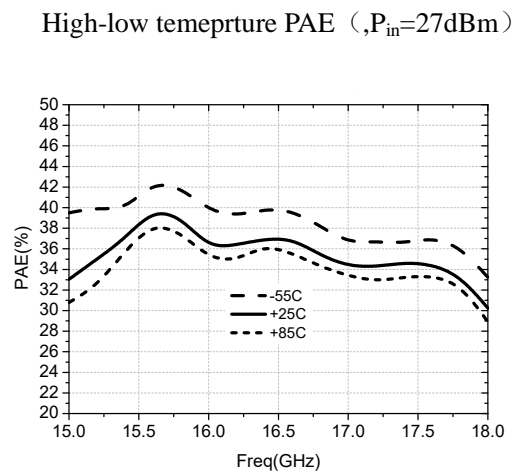
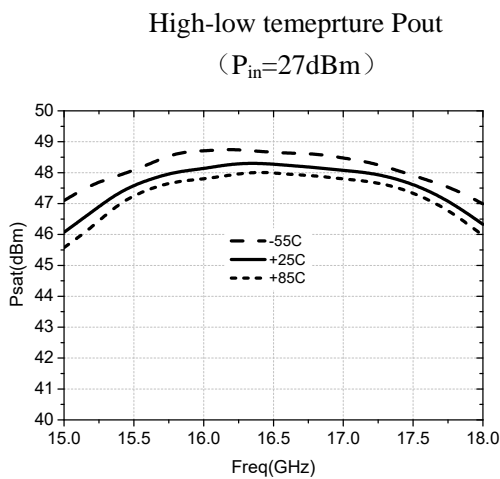
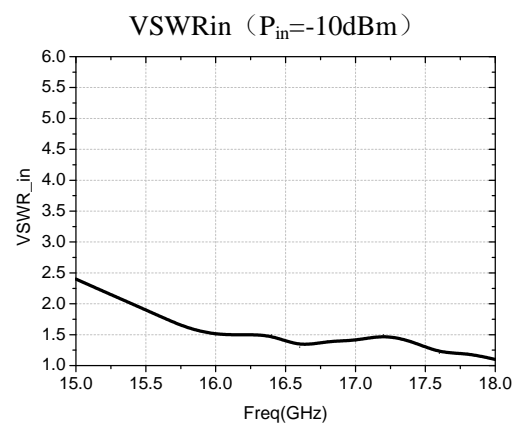
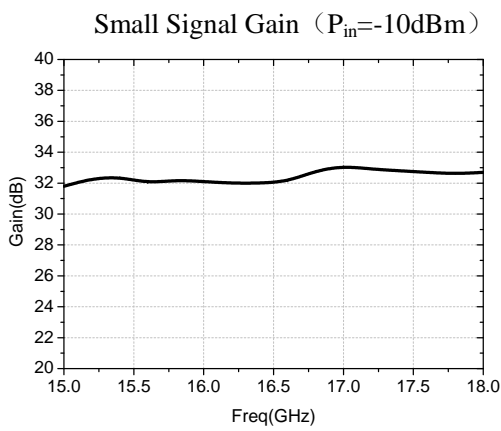
Note : 1) The MMIC has been 100% DC and RF tested on chip.

2) Testing Condition: Vd=+28V, Vg=-1.8V, Pin=27dBm, Pulse width 100μs, duty cycle 10%;

Max Limited Values

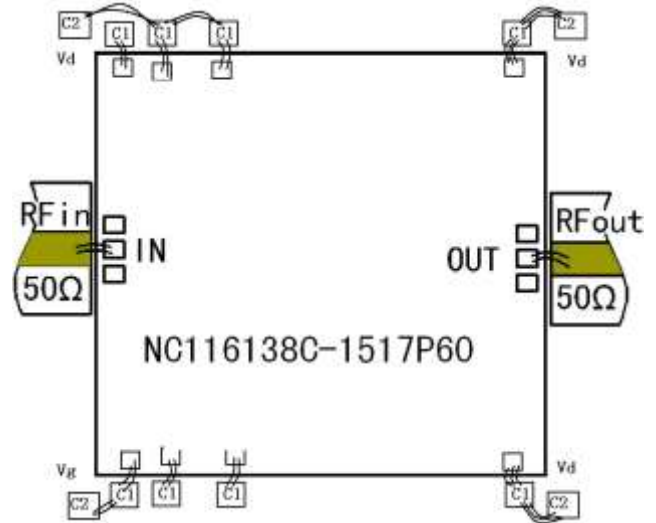
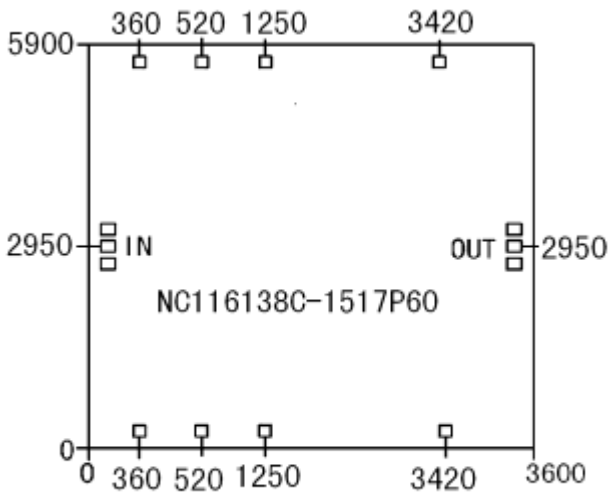
Parameter	Values
Max Vd	+36V
Max Vg	-5V
CW P _p	+32dBm
T _{STG}	-65°C~+150°C
T _{op}	+200°C
Z ₀	5: 1

Testing Curves (Vd=+28V, Vg=-1.8V)



Outline and Dimension

Assembly Diagram



Note : All the unit is μm ;
Input and output pad dimension: $100 \times 120 \mu\text{m}^2$
Bias pad dimension: $100 \times 100 \mu\text{m}^2$

note : External capacitance $c=100\text{pF}, c2=2\text{PF}$;

Please add above $0.01\mu\text{F}$ capacitor filter at the gate bias, the diameter, Bonding wire diameter is $25\mu\text{m}$.

Attention

- 1) The MMIC needs to be stored in a dry and clean N2 environment;
- 2) The chip substrate material 6H-SiC is very brittle and must be used carefully to avoid damage to the chip;
- 3) The thermal expansion coefficient of the carrier should be close to that of 6H-SiC, and the coefficient of thermal expansion of the wire is $4.2 \times 10^{-6}/^\circ\text{C}$. When using continuous wave, it is recommended that the carrier material be copper-molybdenum-copper, copper-molybdenum-copper-copper, diamond-copper, etc.
- 4) Please avoid holes between the chip and the carrier during assembly, and ensure good heat dissipation of the case and carrier;
- 5) It is recommended to use gold tin solder for sintering, Au:Sn=80%: 20%, sintering temperature not exceeding 300°C , time is not longer than 30 seconds, the sintering process avoids rapid temperature change, and needs to gradually rise and fall;
- 6) It is recommended to use a gold wire with a diameter of $25\mu\text{m} \sim 30\mu\text{m}$. The temperature of the bonding platform chassis does not exceed 250°C , the bonding time is as short as possible, and the bonding process avoids rapid temperature changes;
- 7) Pay attention to anti-static during the use and assembly of the chip, wear a grounded anti-static bracelet, and the grounding of the sintering and bonding stations is good;
- 8) If you have any questions, please contact the supplier.